


<b>Search Notes</b>  	<b>Application/Control No.</b>  10575526	<b>Applicant(s)/Patent Under Reexamination</b>  SPITZ ET AL.
	<b>Examiner</b>  Hsin-Yi (Steven) Hsieh	<b>Art Unit</b>  2811

SEARCHED			
Class	Subclass	Date	Examiner
257	706, E23.101	Updated 08/18/10	HH

SEARCH NOTES		
Search Notes	Date	Examiner
Update Search: East search and subclass search	08/18/10	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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